EXPRESS MAIL LABEL NO. EV314044282US

DATED: 1 APRIL 2004 **ATTORNEY DOCKET: MXIC 1571-1**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Inventors:

Group Art Unit: unknown

Chih Chieh Yeh et al.

Examiner: unknown

Application No. _____

Filed: 1 April 2004 (herewith)

CUSTOMER NO. 22470

Title: Integrated Code and Data Flash

Memory

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. §1.56

Sir:

It is requested that the information identified in this statement be considered by the Examiner and made of record in the above-identified application. This statement is not intended to represent that a search has been made or that the information cited in the statement is, or is considered to be, material to patentability as defined in 37 C.F.R. 1.56.

Enclosed with this statement is a Form PTO-SB/08. The Examiner is requested to initial the form and return it to the undersigned in accordance with M.P.E.P. 609.

Also enclosed with this statement is a copy of each cited document as required by 37 C.F.R. 1.98. The exception to this, in accordance with the 05 August 2003 Official Gazette Notice in which the USPTO waives the requirement for submitting copies of U.S. Patent and Publications for cases filed after 30 June 2003, is that copies of U.S. Patent documents and copies of U.S. Patent publications are not being submitted.

If a written English-language translation of a non-English language document, or portion thereof, is within the possession, custody or control of, or is readily available to any individual designated in 1.56(c), a copy of the translation accompanies this statement, 37 C.F.R. 1.98(a)(3)(ii), and satisfies the requirement for a concise explanation of relevance, MPEP 609A(3).

This statement should be considered under 37 C.F.R. 1.97(b) because it is being filed within three months of the filing date of an application other than a continued prosecution application under 37 C.F.R. 1.53(d).

Fee Authorization. The Commissioner is hereby authorized to charge underpayment of any additional fees or credit any overpayment associated with this communication to Deposit Account No. 50-0869 (MXIC 1571-1). A copy of this authorization is enclosed.

> Respectfully submitted, HAYNES BEFFEL & WOLFELD LLP

Date: 31 Man 2004

HAYNES BEFFEL & WOLFELD LLP

P.O. Box 366

Half Moon Bay, CA 94019 Telephone: (650) 712-0340 Facsimile: (650) 712-0263

Please type a plus sign (+) inside this box

+ Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute f	or form 1449A/PTO	,		Co	omplete if Known
				Application Number	
INFO	RMATION	DISC	LOSURE	Filing Date	1 April 2004 (herewith)
STAT	EMENT B	Y AP	PLICANT	First Named Inventor	Chih C. Yeh
				Group Art Unit	
(u	se as many shee	ets as ne	cessary)	Examiner Name	
heet	1	of	3	Attorney Docket Number	MXIC 1571-1

			U.S. PATENT DOC	JMENTS	
Examiner Initials*	Cite No.1	U.S. Patent Document Kind Code Number (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	A1	4,959,812	Momodomi et al	09-25-1990	
	A2	5,270,969	Iwahashi	12-14-1993	
	A3	5,424,569	Prall	06-13-1995	
	A4	5,448,517	Iwahashi	09-05-1995	
	A5	5,515,324	Tanaka	05-07-1996	
	A6	5,644,533	Lancaster et al.	07-01-1997	
	A7	5,768,192	Eitan	06-16-1998	
	A8	6,011,725	Eitan	01-04-2000	
	A9	6,172,907	Jenne	01-09-2001	
	A10	6,215,148	Eitan	04-10-2001	
	A11	6,370,062	Choi	04-09-2002	
	A12	6,436,768	Yang et al.	08-20-2002	
	A13	6,458,642	Yeh et al.	10-01-2002	
	A14	6,487,114	Jong et al.	11-26-2002	
	A15	6,566,699	Eitan	05-20-2003	
	A16	6,614,694	Yeh et al.	09-02-2003	
	A17	6,643,181	Sofer et al.	11-04-2003	
	A18	6,690,601	Yeh et al.	02-10-2004	
	A19	Re. 35,838	Momodomi et al.	07-07-1998	
	A20	2002/0179958	Kim	12-05-2002	

				FORI	EIGN PATENT DOCUMENT	rs		
Examiner	Cite		Foreign Patent Docur		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant	
Initials*	No.1	Office ³	Number ⁴	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	Тв
	B1	JР	09162313A		Atsushi	06-20-1997	-	
	B2	JР	11233653A		Shigeki	08-27-1999		
	B3							\top
	B4							
	B5							
	B6		l <u>. </u>		· · · · · · · · · · · · · · · · · · ·			
	B7							
	B8							
	B9							
	B10							

Examiner	Date	
Signature	Considered	

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

lease type a	plus sign (+)	inside this	box →	\cap
, , , ,	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,			

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitu	ite for form 1449A/PT(>		Co	omplete if Known
				Application Number	
INF	ORMATION	DI	SCLOSURE	Filing Date	1 April 2004 (herewith)
STA	TEMENT B	Y A	PPLICANT	First Named Inventor	Chih C. Yeh
				Group Art Unit	
	(use as many she	ets as	s necessary)	Examiner Name	
Sheet	2	of	3	Attorney Docket Number	MXIC 1571-1

				U.S. PATENT DOCL	JMENTS	,
Examiner Initials*	Cite No.1	Number	nd Code ²	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	A21	2003/013787	3	Kawamura	07-24-2003	
	A22	2003/018505	5	Yeh et al.	10-02-2003	
	A23					
	A24					
	A25					
	A26					
	A27		\Box			
	A28		1 1			
	A29		11			
	A30					
	A31					
,	A32					
	A33		111			
	A34		$\dashv \dashv \dashv$			
	A35		11			
	A36					
	A37					
	A38					
	A39					
	A40					

				FORE	IGN PATENT DOCUMEN	TS		
	Everines Cite	F	oreign Patent Do	cument	Name of Patentee or	Date of Publication of	Pages, Columns, Lines,	
Examiner Initials*	Cite No.1	Office ³	Number4	Kind Code ⁵ (if known)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Where Relevant Passages or Relevant Figures Appear	T ⁶
	B11		<u> </u>					
	B12							
	B13					1	· - ··	
	B14							
	B15				-			1
	B16							
	B17							
	B18							
	B19							
	B20							

Examiner	Date	
	la	
Signature	Considered	
J.3		

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U. S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Assistant Commissioner for Patents, Washington, DC 20231.



^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. 2 See attached Kinds of U.S. Patent Documents. 3 Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). 4 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the senal number of the patent document. 5 Kind of document by the appropriate symbols as indicated on the document under MPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Please type a plus sign (+) inside this box -> +	Please t	уре а	plus	sign (+)	inside	this	box		\Box
--	----------	-------	------	----------	--------	------	-----	--	--------

PTO/SB/08B (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

U. S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

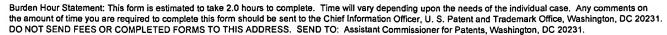
Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitu	ute for form 1449B/PTC	5		Co	mplete if Known
				Application Number	
INF	ORMATION		ISCLOSURE	Filing Date	1 April 2004 (herewith)
STA	TEMENT F	RY	APPLICANT	First Named Inventor	Chih C. Yeh
0.7			ALL EIGAIT	Group Art Unit	
	(use as many s	sheets	as necessary)	Examiner Name	
Sheet	3	of	3	Attorney Docket Number	MXIC 1571-1

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
	C1	BLOOM, ILAN, et al., "2-Bit Cell NV Memory Minimizes Chip Area with Less Masks," Nikkei Electronics Asia, January 2002, 11 pages	
_	C2	DE BLAUWE, JAN, "Nanocrystal Nonvolatile Memory Devices," IEEE Transactions on Nanotechnology, Vol. 1, No. 1, March 2002, 72-77.	
	C3	HIROSE, M., "Challenges for Future Semiconductor Development," International Microprocess and Nanotechnology Conference, 6 November 2002, 47 pages.	
	C4	LEE, JAE-DUK, et al., "Effects of Floating-Gate Interference on NAND Flash Memory Cell Operation," IEEE Electron Device Letters, Vol. 23, No. 5, May 2002, 264-266.	
	C5	SHIN, YOOCHEOL, et al., "High Reliable SONOS-type NAND Flash Memory Cell with Al2O3 for Top Oxide," Non-Volatile Semiconductor Memory Workshop, 2003, 2 pages.	
	C6	LEE, CHANGHYUN, et al., "A Novel Structure of SiO2/SiN/High k Dielectrics, Al2O3 for SONOS Type Flash Memory," Extended Abstracts of the 2002 International Conference on Solid State Devices and Materials, Nagoya, Japan, 2002, 162-163.	
	C7	YEH, C.C., et al., "PHINES: A Novel Low Power Program /Erase, Small Pitch, 2-Bit per Cell Flash Memory," IEEE IEDM, 2002, 931-934.	
	C8	PRINZ, E.J., et al., "An Embedded 90nm SONOS Flash EEPROM Utilizing Hot Electron Injection Programming and 2-Sided Hot Hole Injection Erase," NVM Workshop 2003, 2 pages.	
	C9	RUDEN, P. PAUL, et al., "Modeling of band-to-band tunneling transitions during drift in Monte Carlo transport simulations," J. Appl. Phys., Vol. 88, No. 3, 1 August 2000, 1488-1493.	
	C10	LEE, CHANG HYUN, et al., "A Novel SONOS Structure of SiO2/SiN/Al2O3 with TaN Metal Gate for Multi-Giga Bit Flash Memeries," IEEE 2003, 4 pages.	
	СП	CHUNG, STEVE S., et al., "A Novel Leakage Current Separation Technique in a Direct Tunneling Regime Gate Oxide SONOS Memory Cell," IEEE 2003, 4 pages.	

Examiner	Date	
Signature	Considered	

¹ Unique citation designation number. 2 Applicant is to place a check mark here if English language Translation is attached.



^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.